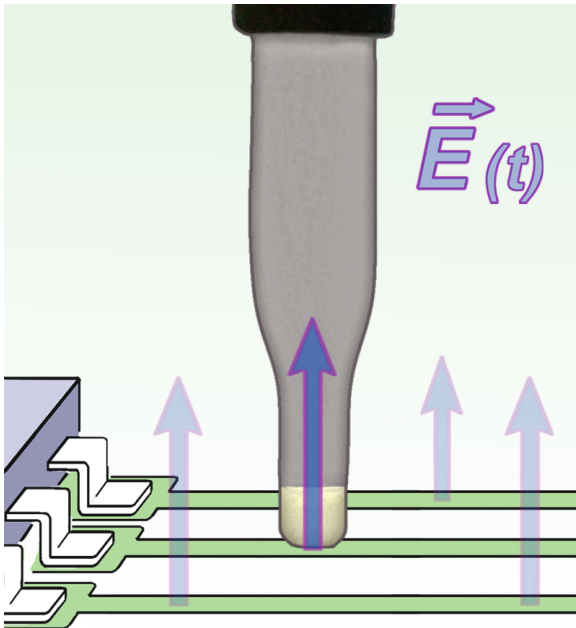


XFS-E 10

Scanner Probe 30 MHz up to 6 GHz



Short description

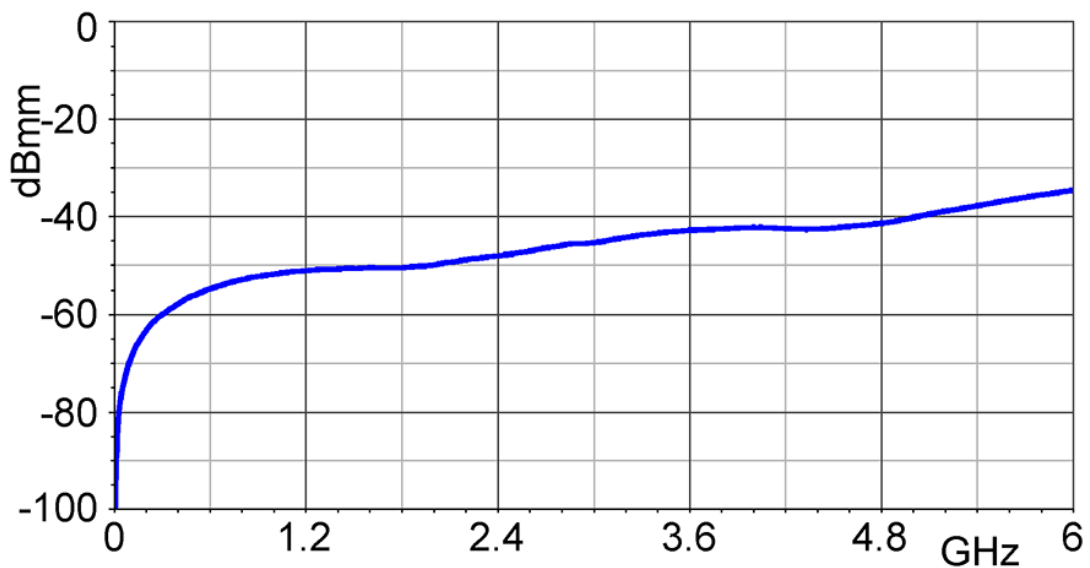
The electrode in the probe head of the XFS-E 10 scanner probe has a width of approx. 0.2 mm. With the probe even smallest E-field sources can be located, e.g. conducting paths with a width of 0.1 mm or single pins on multi pinned ICs. To measure, the E-field probe is positioned onto the object.

The XFS-E 10 probe is a passive near-field probe. Normally the probe head is positioned directly onto the measured object (high electric field strength). It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50 Ω input. The H-field scanner probe has an internal terminating resistance.

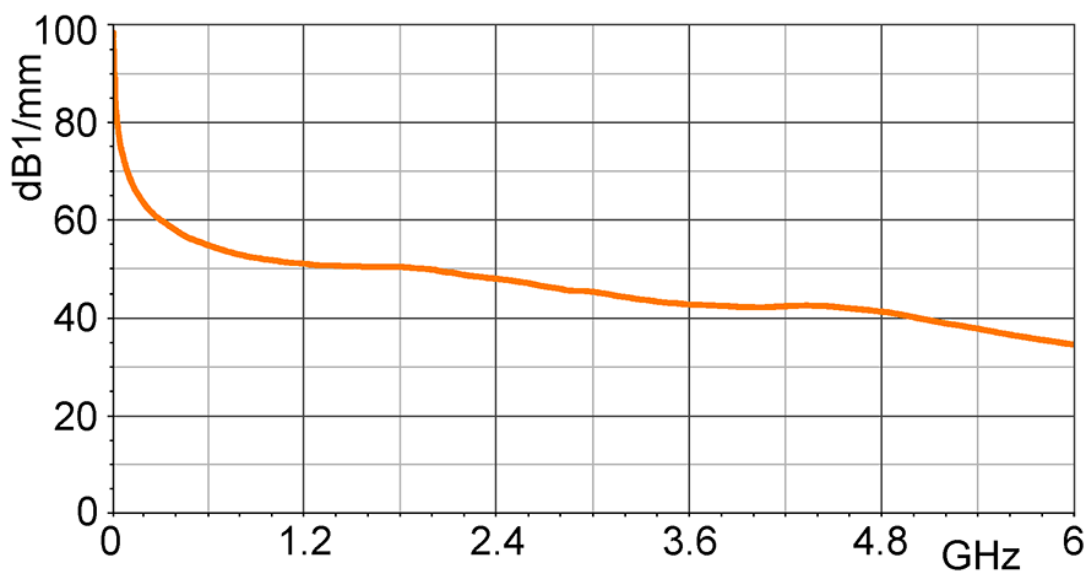
Technical parameters

Frequency range	30 MHz ... 6 GHz
Resolution	≈ 0.2 mm
Probe head dimensions:	$\approx (0.5 \times 2)$ mm
Connector - output	SMA, male, jack

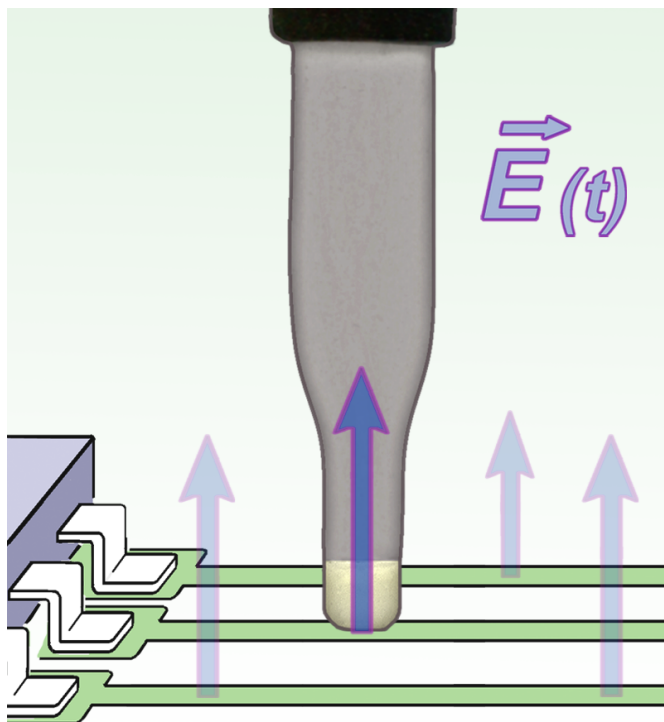
Frequency response [dB μ V] / [dB μ A/m]



E- field correction curve [dB μ V/mm] / [dB μ V]



Measuring principles



XFS-E 10

Scanner Probe 30 MHz up to 6 GHz

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